

<b>Notice of References Cited</b>	Application/Control No. 10/522,468	Applicant(s)/Patent Under Reexamination CHANG, WEI-BIN	
	Examiner Leonard Saint-Cyr	Art Unit 2626	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2003/0152261	08-2003	Hiroe et al.	382/153
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